

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

| Supplier Nexperia B.V. | | User Part Number | | | | | | |
|---|----------------------------------|--|-------------|-----------|------------|-----------|--|--|
| | | PDTA143EQC-Q | | | | | | |
| Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test | | Part Description | | | | | | |
| | | Nexperia DHAM Small Signal Bipolar Transistor | | | | | | |
| | | MCD package | | | | | | |
| | | Test Conditions | Duration | # Lots | # Quantity | # Rejects | | |
| | TEST | | | | | | | |
| | Pre- and Post-Stress | | | | | | | |
| # E1 | Electrical Test | Tamb = 25 °C | N/A | see below | all parts | see below | | |
| | | JESD22-A113 | | | | | | |
| | | Bake Tamb = 125 °C | 24 hours | | | | | |
| | PC | Soak Tamb = 85 °C, RH = 85% | 168 hours | | | | | |
| # A1 | Preconditioning | Reflow soldering | 3 cycles | 464 | 20960 | 0 | | |
| | | MIL-STD-750-1 | | | | | | |
| | HTRB | M1039 Method A | | | | | | |
| | High Temperature Reverse Bias | Tj = Tjmax, Vr = 100% of max. datasheet | | | | _ | | |
| # B1 | Bias | reverse voltage | 1000 hours | 415 | 18680 | 0 | | |
| | | JECD22 4404 | | | | | | |
| | TC Temperature Cycling | JESD22-A104 -65 °C to Tjmax, not to exceed 150°C | 1000 | | F2.40 | • | | |
| # A4 | remperature Cycling | -63 °C to Tjillax, flot to exceed 130°C | 1000 cycles | 116 | 5240 | 0 | | |
| | UHAST | JESD22-A118 | | | | | | |
| # A3 or | Unbiased HAST | Tamb = 130 °C, RH = 85 % | — 96 hours | 116 | 5240 | 0 | | |
| , 713 01 | Cribiasea rivis r | <u>, </u> | | | | | | |
| | AC | JESD22-A102 Tamb = 121 °C, RH = 100 % | | | | | | |
| # A3 alt | Autoclave | Pressure = 205 kPa (29.7 psia) | | | | | | |
| # AJ alt | , late ella ve | Tressure Les in a (Esti pola) | | | | | | |
| | H3TRB | JESD22-A101 | | | | | | |
| | High Humidity High | Tamb = 85 °C, RH = 85%, VR = 80 % of | | | | | | |
| # A2 alt | | rated reverse voltage ^[1] | 1000 hours | 116 | 5240 | 0 | | |
| 12 aic | p | MIL-STD-750 Method 1037 | 2000 110013 | -10 | 3210 | | | |
| | IOL | ton = toff, devices powered to insure ΔT_j = | | | | | | |
| # A5 | Intermittent Operating Life | | 1000 hours | 116 | 5240 | 0 | | |
| | | | | | | - | | |
| | RSH | JESD22-A111 | | | | | | |
| # C8 | Resistance to Solder Heat | 260 °C ± 5 °C | 10 s | n.a. | n.a. | n.a. | | |
| | SD | | | | | | | |
| # C10 | Solderability | J-STD-002 | | 86 | 2580 | 0 | | |

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab | Technology | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|-----------|----------------------|----------|---------|--------------------|------------|
| Nexperia | Small Signal Bipolar | | | | |
| DHAM | Transistor | 18680 | 0 | 0,23 | 4,40E+09 |

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